

Short Course on Microwave Measurements and Instrumentation

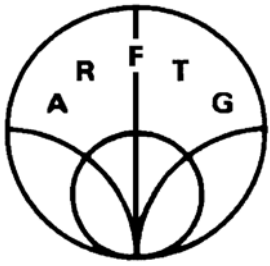
December 2-3, 2003
Boulder, Colorado



PRELIMINARY AGENDA

Tuesday, December 2

- 7:30 a.m. – 8:00 a.m. **Registration**
- 8:00 a.m. – 9:15 a.m. **VNA Error Models and Calibration Methods**
Doug Rytting – Agilent
- 9:15 a.m. – 9:50 a.m. **RF Connectors and Transmission Lines**
John Juroshek – NIST
- 9:50 a.m. – 10:20 a.m. **Break**
- 10:20 a.m. – 11:00 a.m. **VNA Uncertainty**
John Juroshek – NIST
- 11:00 a.m. – 12:15 p.m. **Microwave Power Measurements**
Tom Crowley – NIST
- 12:15 p.m. – 1:30 p.m. **Lunch**
- 1:30 p.m. – 2:00 p.m. **Accurate On-Wafer Measurement**
Dylan Williams - NIST
- 2:00 p.m. – 2:45 p.m. **Introduction to Optoelectronic Measurements**
Paul Hale – NIST
- 2:45 p.m. – 3:05 p.m. **Break**
- 3:05 p.m. – 3:45 p.m. **Practical Oscilloscope Measurements**
Tracy Clement – NIST
- 3:45 p.m. – 5:00 p.m. **Thermal Noise Measurements**
Jim Randa – NIST



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Wednesday, December 3

- 8:00 a.m. – 8:50 a.m. **Uncertainty Analysis**
Nick Ridler – NPL
- 8:50 a.m. – 9:35 a.m. **Phase Noise Measurements**
Ed Godshalk – Maxim
- 9:35 a.m. – 10:15 a.m. **Large-Signal Network Analysis – Part I**
Jan Verspecht – Jan Verspecht bvba
- 10:15 a.m. – 10:30 a.m. **Break**
- 10:30 a.m. – 11:15 p.m. **Large-Signal Network Analysis – Part II**
Jan Verspecht – Jan Verspecht bvba
- 11:15 a.m. – 12:00 p.m. **EMC in the Measurement Laboratory**
Howard Reader – University of Stellenbosch